

March 2014

# FQA8N100C

# N-Channel QFET® MOSFET

1000 V, 8 A, 1.45 Ω

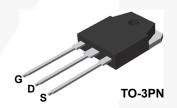
## **Features**

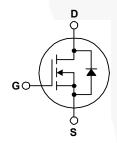
- $R_{DS(on)}$  = 1.45  $\Omega$  (Max.) @  $V_{GS}$  = 10 V,  $I_D$  = 4 A
- Low Gate Charge (Typ. 53 nC)
- Low Crss (Typ. 16 pF)
- · 100% Avalanche Tested

## **Description**

These N-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar stripe, DMOS technology.

This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for high efficient switched mode power supplies.





## Absolute Maximum Ratings T<sub>C</sub> = 25°C unless otherwise noted.

Symbol	Parameter		FQA8N100C	Unit	
V <sub>DSS</sub>	Drain-Source Voltage		1000	V	
I <sub>D</sub>	Drain Current - Continuous ( $T_C = 25^{\circ}C$ ) - Continuous ( $T_C = 100^{\circ}C$ )		8 5	A A	
I <sub>DM</sub>	Drain Current - Pulsed (N	Note 1)	32	Α	
V <sub>GSS</sub>	Gate-Source voltage		±30	V	
E <sub>AS</sub>	Single Pulsed Avalanche Energy		850	mJ	
I <sub>AR</sub>	Avalanche Current (N	(Note 1) 8		Α	
E <sub>AR</sub>	Repetitive Avalanche Energy (N	Note 1)	22.5	mJ	
dv/dt	Peak Diode Recovery dv/dt (N	Note 3)	4.0	V/ns	
$P_{D}$	Power Dissipation (T <sub>C</sub> = 25°C) - Derate above 25°C		225 1.79	W W/°C	
T <sub>J,</sub> T <sub>STG</sub>	Operating and Storage Temperature Range		-55 to +150	°C	
T <sub>L</sub>	Maximum Lead Temperature for Soldering Purpose, 1/8" from Case for 5 Seconds		300	°C	

## **Thermal Characteristics**

Symbol	Parameter	FQA8N100C	Unit	
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case, Max.	0.56	°C/W	
$R_{\theta CS}$	Thermal Resistance, Case-to-Sink, Typ.	0.24	°C/W	
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient, Max.	40	°C/W	

# **Package Marking and Ordering Information**

Part Number	Top Mark	Package	Packing Method	Reel Size	Tape Width	Quantity
FQA8N100C	FQA8N100C	TO-3PN	Tube	N/A	N/A	30 units

# **Electrical Characteristics** $T_C = 25^{\circ}C$ unless otherwise noted.

Symbol	Parameter	Conditions		Тур.	Max.	Unit
Off Charac	teristics				•	•
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	V <sub>GS</sub> = 0V, I <sub>D</sub> = 250μA	1000			V
ΔBV <sub>DSS</sub> / ΔT <sub>J</sub>	Breakdown Voltage Temperature Coefficient	I <sub>D</sub> = 250μA, Referenced to 25°C		1.4		V/°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> = 1000V, V <sub>GS</sub> = 0V V <sub>DS</sub> = 800V, T <sub>C</sub> = 125°C			10 100	μ <b>Α</b> μ <b>Α</b>
I <sub>GSSF</sub>	Gate-Body Leakage Current, Forward	V <sub>GS</sub> = 30V, V <sub>DS</sub> = 0V	-		100	nA
I <sub>GSSR</sub>	Gate-Body Leakage Current, Reverse	V <sub>GS</sub> = -30V, V <sub>DS</sub> = 0V	-		-100	nA
On Charac	teristics					•
V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	3.0		5.0	V
R <sub>DS(on)</sub>	Static Drain-Source On-Resistance	V <sub>GS</sub> = 10V, I <sub>D</sub> = 4A		1.2	1.45	Ω
9 <sub>FS</sub>	Forward Transconductance	V <sub>DS</sub> = 50V, I <sub>D</sub> = 4A	-	8.0		S
Dynamic C	Characteristics					
C <sub>iss</sub>	Input Capacitance	V <sub>DS</sub> = 25V, V <sub>GS</sub> = 0V,	\	2475	3220	pF
C <sub>oss</sub>	Output Capacitance	f = 1.0MHz		195	255	pF
C <sub>rss</sub>	Reverse Transfer Capacitance		-	16	24	pF
Switching	Characteristics					
t <sub>d(on)</sub>	Turn-On Delay Time	V <sub>DD</sub> = 500V, I <sub>D</sub> = 8A		50	110	ns
t <sub>r</sub>	Turn-On Rise Time	$R_{G} = 25\Omega$		95	200	ns
t <sub>d(off)</sub>	Turn-Off Delay Time			122	254	ns
t <sub>f</sub>	Turn-Off Fall Time	(Note 4)		80	170	ns
Qg	Total Gate Charge	V <sub>DS</sub> = 800V, I <sub>D</sub> = 8A	/	53	70	nC
Q <sub>gs</sub>	Gate-Source Charge	V <sub>GS</sub> = 10V	/	13		nC
Q <sub>gd</sub>	Gate-Drain Charge	(Note 4)	-	23		nC
Drain-Soul	rce Diode Characteristics and Maximun	n Ratings		I	y	l
Maximum Continuous Drain-Source Diode Forward Current					8	Α
I <sub>SM</sub>	Maximum Pulsed Drain-Source Diode Forward Current				32	Α
$V_{SD}$	Drain-Source Diode Forward Voltage	V <sub>GS</sub> = 0V, I <sub>S</sub> = 8A			1.4	V
t <sub>rr</sub>	Reverse Recovery Time	V <sub>GS</sub> = 0V, I <sub>S</sub> = 8A		620		ns
Q <sub>rr</sub>	Reverse Recovery Charge	dI <sub>F</sub> /dt =100A/μs		5.2		μС

#### NOTES

<sup>1.</sup> Repetitive rating: pulse-width limited by maximum junction temperature.

<sup>2.</sup> L = 25 mH, I  $_{AS}$  = 8 A, V  $_{DD}$  = 50 V, R  $_{G}$  = 25  $\Omega,$  starting T  $_{J}$  = 25  $^{\circ}C.$ 

 $<sup>3.</sup>I_{SD} \leq 8 \text{ A, di/dt} \leq 200 \text{ A/}\mu\text{s, V}_{DD} \leq \text{BV}_{DSS}\text{, starting T}_{J} = 25^{\circ}\text{C}.$ 

<sup>4.</sup> Essentially independent of operating temperature typical characteristics.

## **Typical Performance Characteristics**

Figure 1. On-Region Characteristics

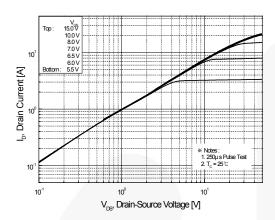


Figure 3. On-Resistance Variation vs.

Drain Current and Gate Voltage

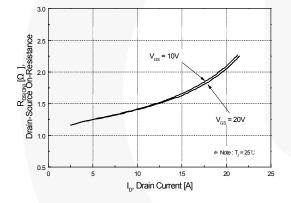


Figure 2. Transfer Characteristics

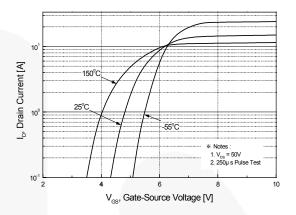


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperatue

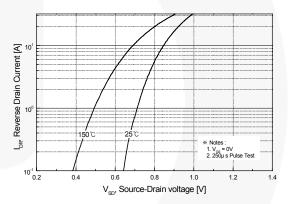
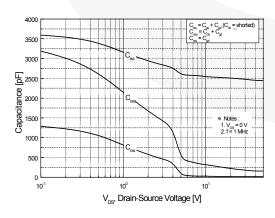
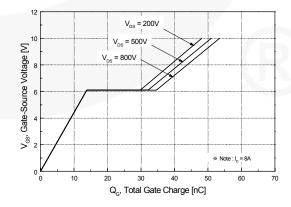


Figure 5. Capacitance Characteristics



**Figure 6. Gate Charge Characteristics** 



## Typical Performance Characteristics (Continued)

Figure 7. Breakdown Voltage Variation vs. Temperature

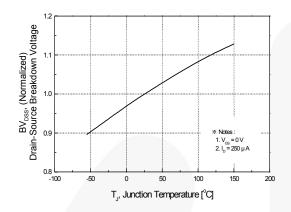


Figure 8. On-Resistance Variation vs. Temperature

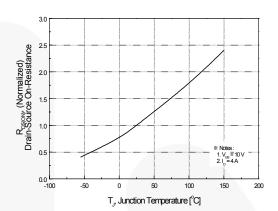


Figure 9. Maximum Safe Operating Area

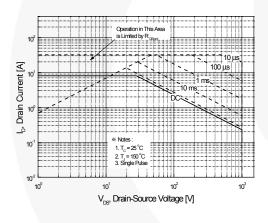


Figure 10. Maximum Drain Current vs. Case Temperature

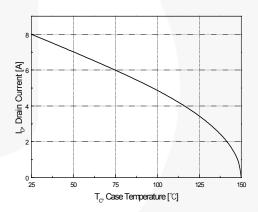
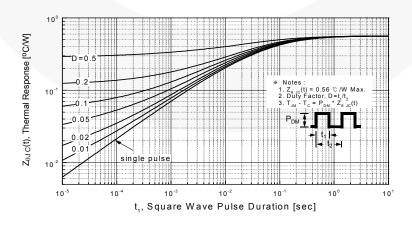


Figure 11. Transient Thermal Response Curve



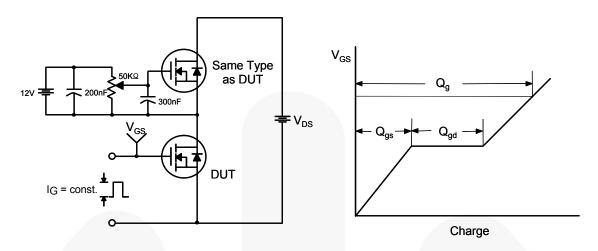


Figure 12. Gate Charge Test Circuit & Waveform

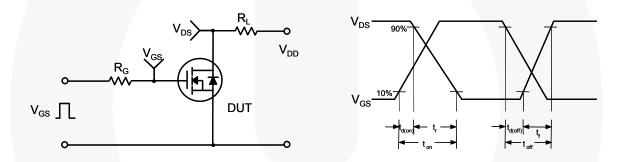


Figure 13. Resistive Switching Test Circuit & Waveforms

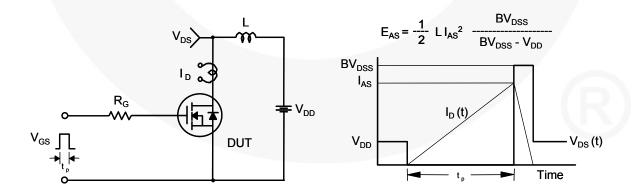


Figure 14. Unclamped Inductive Switching Test Circuit & Waveforms

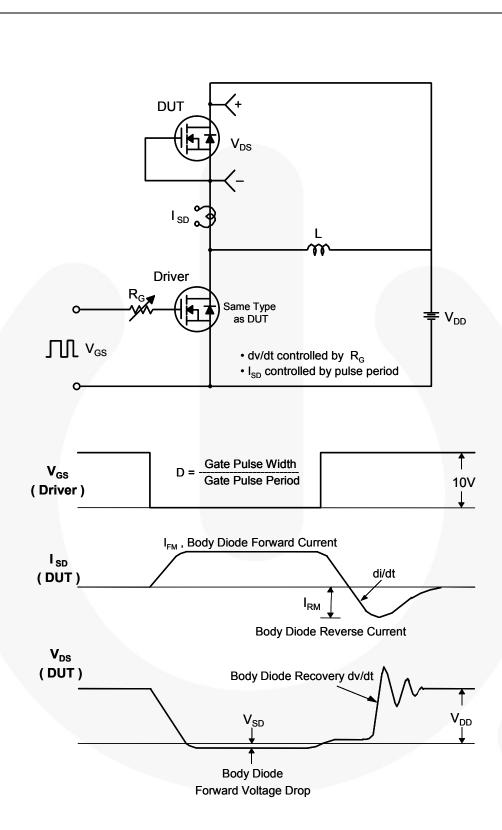
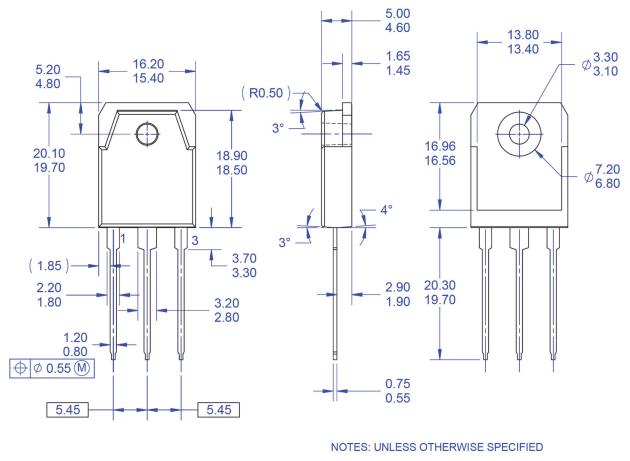
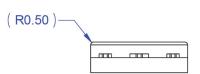


Figure 15. Peak Diode Recovery dv/dt Test Circuit & Waveforms

## **Mechanical Dimensions**





- A) THIS PACKAGE CONFORMS TO EIAJ SC-65 PACKAGING STANDARD.
- ALL DIMENSIONS ARE IN MILLIMETERS.
- **DIMENSION AND TOLERANCING PER** ASME14.5-2009.
- D) DIMENSIONS ARE EXCLUSSIVE OF BURRS, MOLD FLASH, AND TIE BAR EXTRUSSIONS.
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## Figure 16. TO3PN, 3-Lead, Plastic, EIAJ SC-65

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